

Features

- Uses PingWei advanced PerfectMOS technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent $Q_g \times R_{DS(on)}$ product(FOM)
- Excellent Low Ciss
- Qualified according to JEDEC criteria

Benefits

- High robustness and reliability
- Increases maximum current capability
- Low power loss, high power density
- Easy paralleling

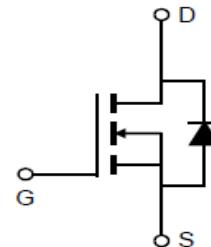
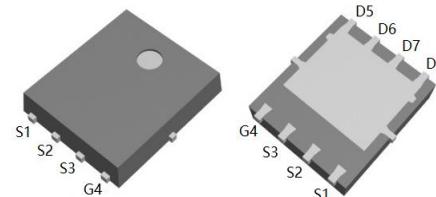
Applications

- Synchronous Rectification for AC/DC Quick Charger
- Battery management
- UPS (Uninterruptible Power Supplies)

**100% DVDS Tested****100% AvalancheTested****Product Summary**

V_{DS}	30V
$R_{DS(on)}@10V$ typ	0.46mΩ
$R_{DS(on)}@4.5V$ typ	0.82mΩ
I_D	150A

DFN5*6

**Package Marking and Ordering Information**

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
PWC006N03ESL2-R	C006N03ESL2	DFN5*6	Tape&Reel	13 inches	12mm	5000pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	30	V
Continuous drain current $T_c = 25^\circ\text{C}$ (Silicon limit) $T_c = 25^\circ\text{C}$ (Package limit) $T_c = 100^\circ\text{C}$ (Silicon limit) $T_a = 25^\circ\text{C}$	I_D	516 150 150 41	A
Pulsed drain current ($T_c = 25^\circ\text{C}$)	$I_{D\text{ pulse}}$	600	A
Avalanche energy, single pulse ($L=0.3\text{mH}$)	E_{AS}	436	mJ
Gate-Source voltage	V_{GS}	± 20	V
Power dissipation $T_c = 25^\circ\text{C}$ $T_a = 25^\circ\text{C}$	P_{tot}	253 1.6	W
Operating junction and storage temperature	T_j, T_{stg}	-55...+150	°C
Soldering temperature, wave soldering only allowed at leads (1.6mm from case for 10s)	T_{sold}	260	°C

Thermal Resistance

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Thermal resistance, junction – case.	R _{thJC}	-	-	0.5	°C/W	-
Thermal resistance, junction - ambient(min. footprint)	R _{thJA}	-	-	80	°C/W	-

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV _{DSS}	30	-	-	V	V _{GS} =0V, I _D =250uA
Gate threshold voltage	V _{GS(th)}	1.0	-	2.5	V	V _{DS} =V _{GS} , I _D =250uA
Zero gate voltage drain current	I _{DSS}	-	-	1	μA	V _{DS} =30V, V _{GS} =0V T _j =25°C T _j =150°C
-	-	-	-	100	-	
Gate-source leakage current	I _{GSS}	-	-	±100	nA	V _{GS} =±20V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	0.46	0.6	mΩ	V _{GS} =10V, I _D =30A
-	-	0.82	1.1		V _{GS} =4.5V, I _D =30A	
Transconductance	g _{fs}	-	161	-	S	V _{DS} =5V, I _D =30A

Dynamic Characteristic

Input Capacitance	C _{iss}	-	6765	-	pF	V _{GS} =0V, V _{DS} =15V, f=100KHz ¹⁾
Output Capacitance	C _{oss}	-	3867	-		
Reverse Transfer Capacitance	C _{rss}	-	85	-		
Gate Total Charge	Q _G	-	85	-	nC	V _{DS} =15V, I _D =30A , V _{GS} =10V
Gate-Source charge	Q _{gs}	-	20	-		
Gate-Drain charge	Q _{gd}	-	8	-		
Turn-on delay time	t _{d(on)}	-	19	-		
Rise time	t _r	-	22	-		
Turn-off delay time	t _{d(off)}	-	54	-	ns	V _{GS} =10V, V _{DD} =15V, R _{G_ext} =1.6Ω, I _D =15A
Fall time	t _f	-	8	-		
Gate resistance	R _G	-	0.9	-		

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	-	-	1.2	V	$V_{GS}=0V, I_{SD}=30A$
Body Diode Continuous Forward Current	I_S	-	-	150	A	$T_C = 25^\circ C$
Body Diode Pulsed Current	$I_{S\text{ pulse}}$	-	-	600	A	$T_C = 25^\circ C$
Body Diode Reverse Recovery Time	t_{rr}	-	175	-	ns	$I_F=30A,$ $dI/dt=100A/\mu s$
Body Diode Reverse Recovery Charge	Q_{rr}	-	0.39	-	uC	

1)100% FT tested at VDS=15V, f=1MHz.

Typical Performance Characteristics

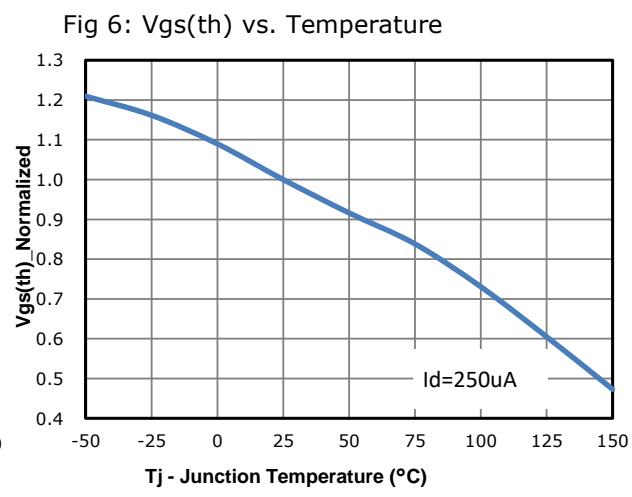
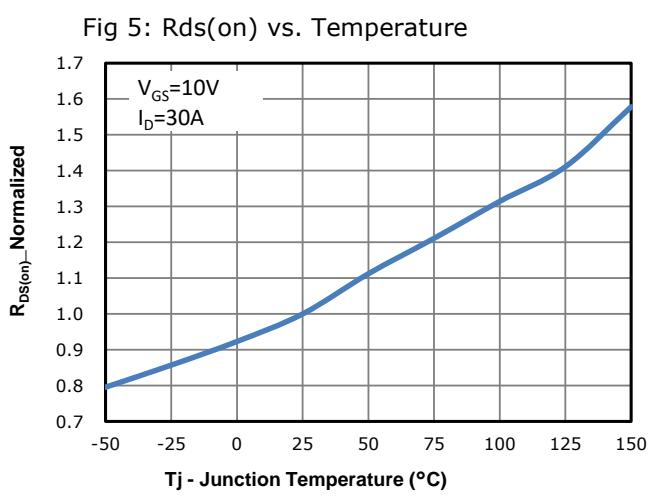
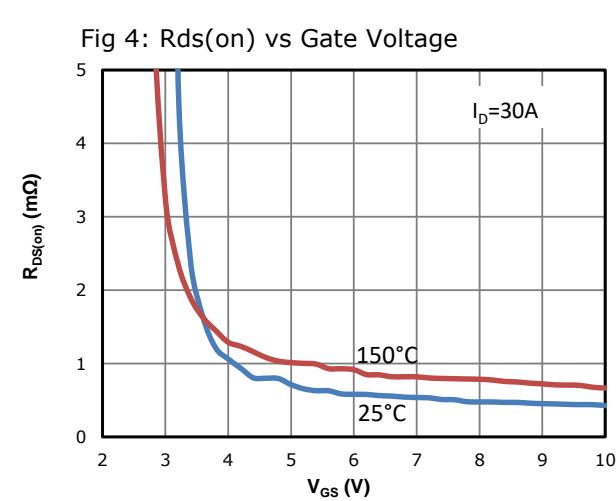
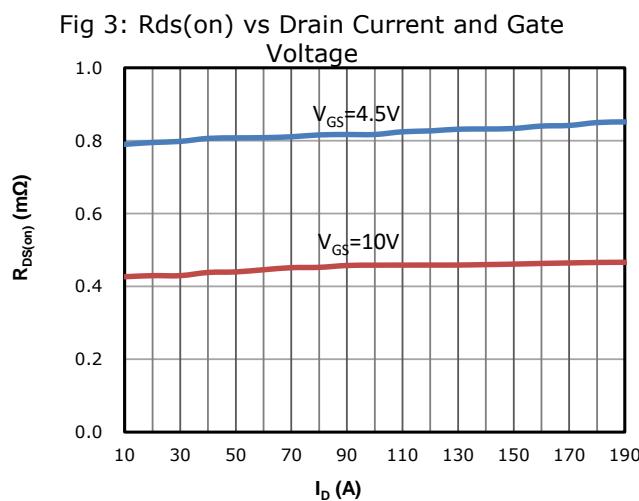
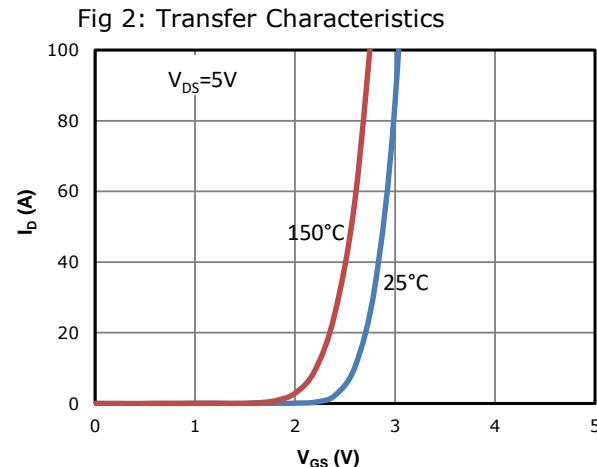
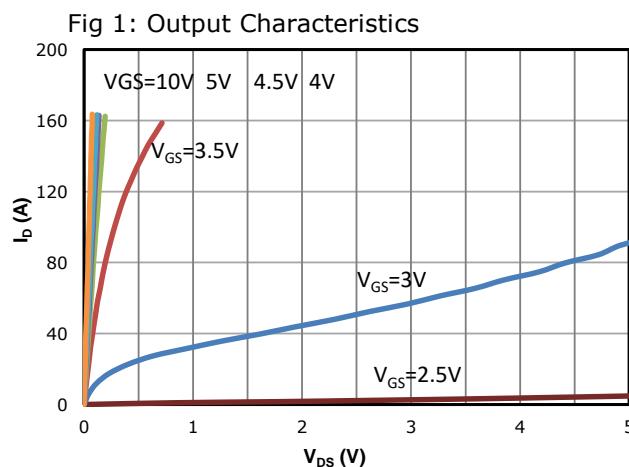


Fig 7: BV_{DSS} vs. Temperature

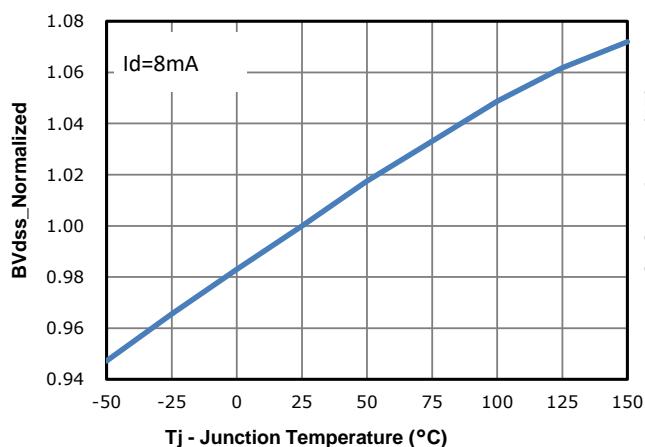


Fig 8: Capacitance Characteristics

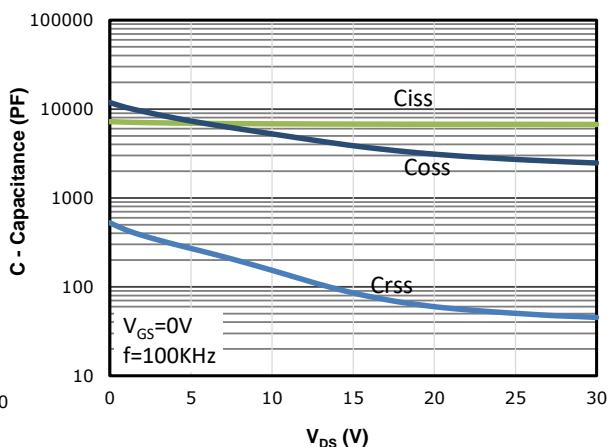


Fig 9: Gate Charge Characteristics

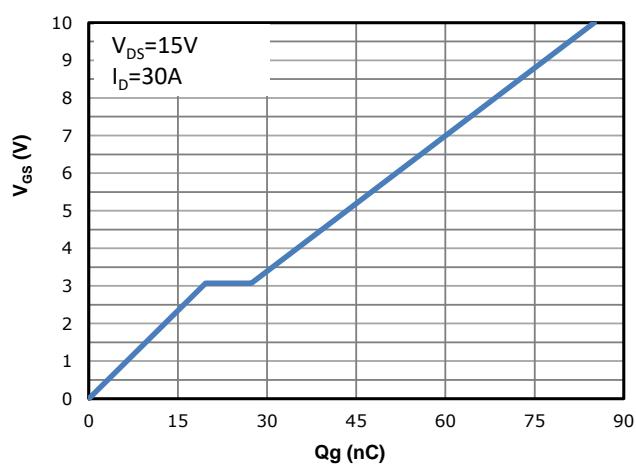


Fig 10: Body-diode Forward Characteristics

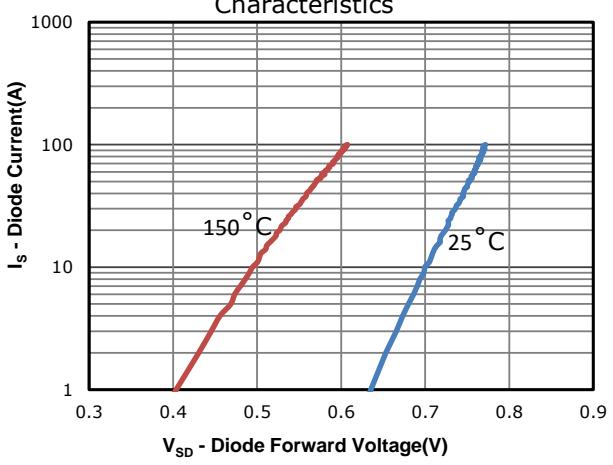


Fig 11: Power Dissipation

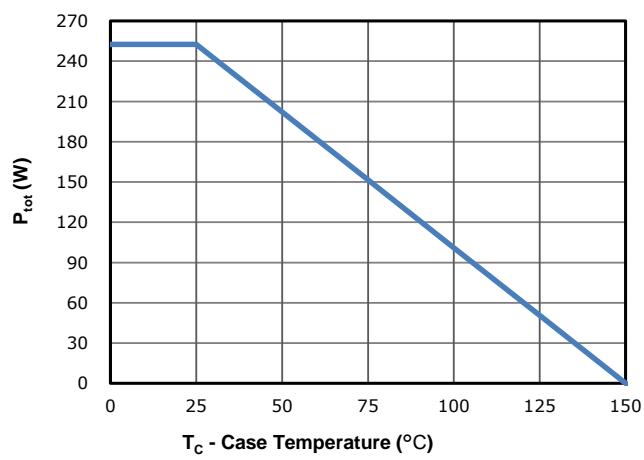


Fig 12: Drain Current Derating

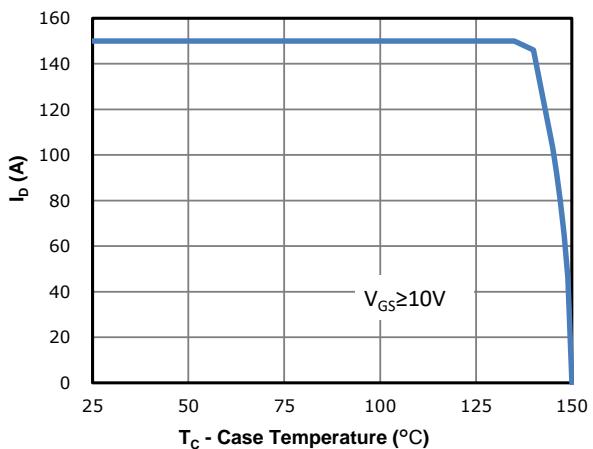


Fig 13: Safe Operating Area

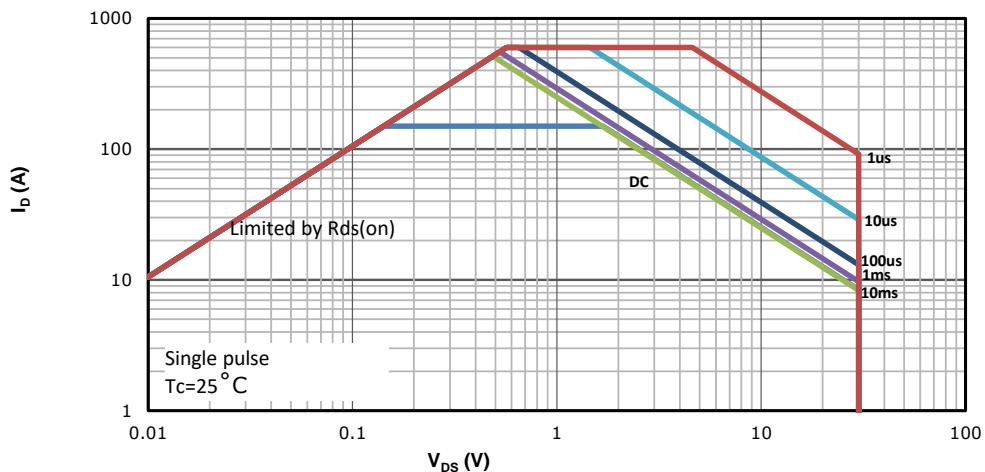
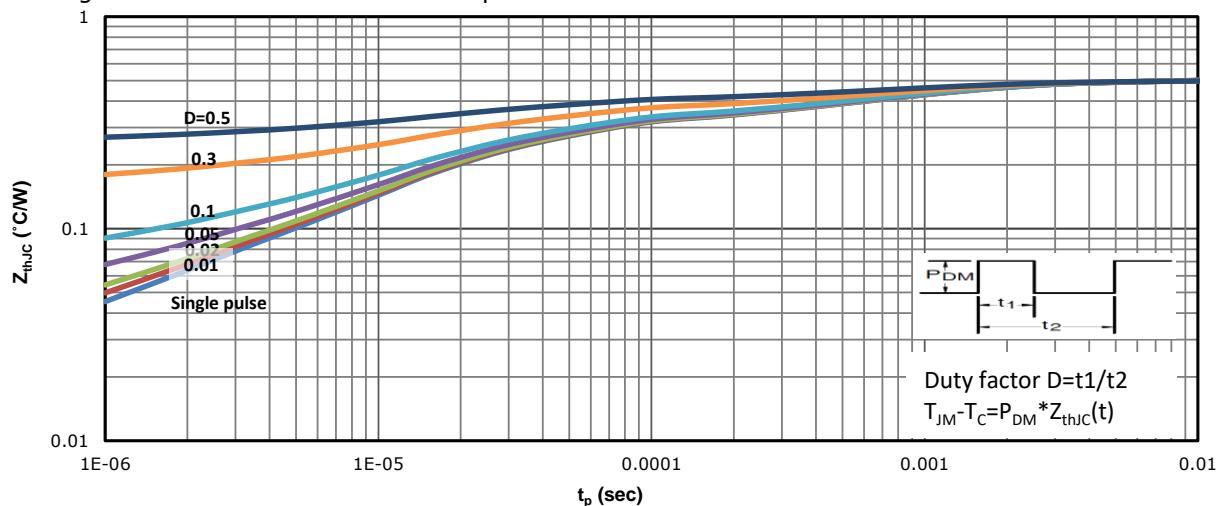
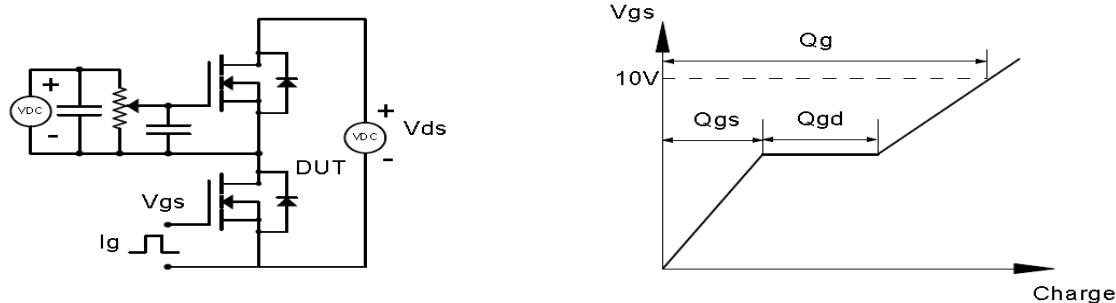


Fig 14: Max. Transient Thermal Impedance

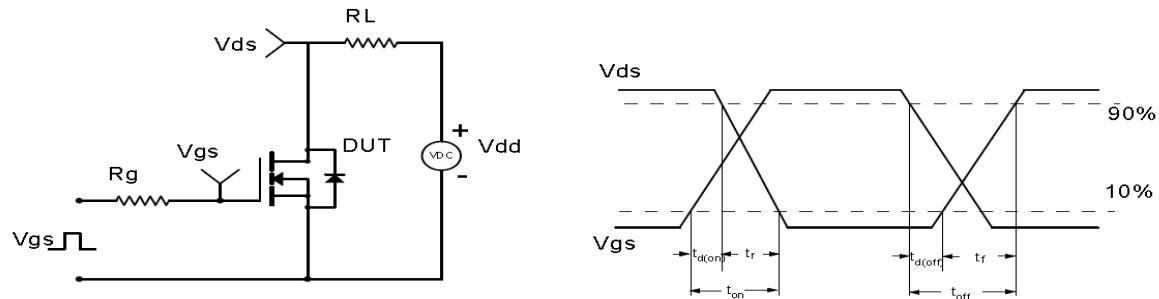


Test Circuit & Waveform

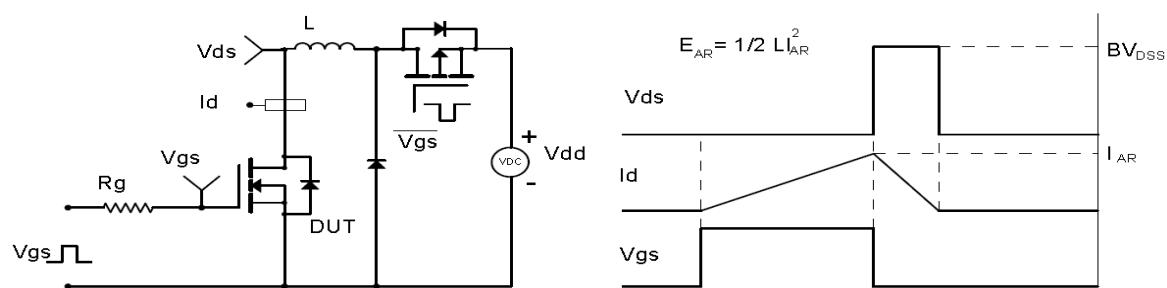
Gate Charge Test Circuit & Waveform



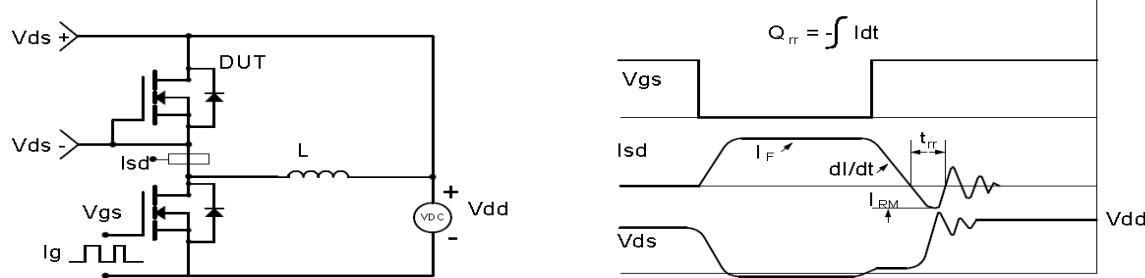
Resistive Switching Test Circuit & Waveforms



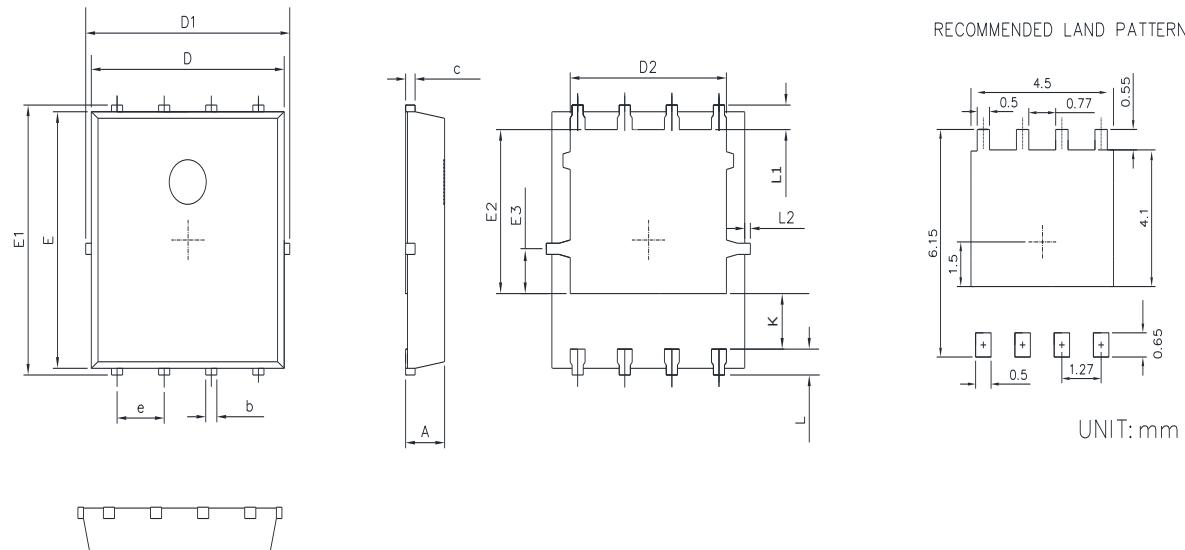
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: DFN5X6



SYMBOL	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0.90	1.10	0.035	0.043
b	0.25	0.50	0.010	0.020
c	0.10	0.30	0.004	0.012
D	4.80	5.30	0.189	0.209
D1	4.90	5.50	0.193	0.217
D2	3.92	4.20	0.154	0.165
E	5.65	5.85	0.222	0.230
E1	5.90	6.20	0.232	0.244
E2	3.33	3.78	0.131	0.149
E3	0.80	1.00	0.031	0.039
e	1.27		0.050	
L	0.40	0.70	0.016	0.028
L1	0.65		0.026	
L2	0.00	0.15	0.000	0.006
K	1.00	1.50	0.039	0.059

Disclaimer

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